

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Appl. No. : TBD
Applicant : Yuichiro Sasaki et al.
Filed : Herewith
Title : "BEAM CURRENT MEASURING APPARATUS AND
BEAM CURRENT MEASURING METHOD USING THE
SAME"

Confirmation No. : TBD
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Customer No. : 052054
Docket No. : 38771

INFORMATION DISCLOSURE STATEMENT

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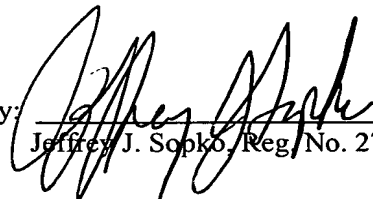
In accordance with Rule 56, applicants are aware of the publications listed in the International Search Report (ISR, copy enclosed) and in the enclosed copy of Patent Office Form 1449. Copies of the publications cited in the International Search Report are not enclosed as they were previously forwarded by the International Bureau.

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Respectfully submitted,

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U.S. PATENT DOCUMENTS

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	A						
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FOREIGN PATENT DOCUMENTS

		Document No.	Date	Country	Class	Subclass	Translation
	L	2001-91611	04/2001	JAPAN			Cited on ISR
	M	2003-21670	01/2003	JAPAN			Cited on ISR
	N	2003-31176	01/2003	JAPAN			Cited on ISR
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OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

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